## Notice of References Cited Application/Control No. 10/721,017 Examiner john walsh Applicant(s)/Patent Under Reexamination WILLGING ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0177261	09-2003	Sekiguchi et al.	709/238
*	В	US-2004/0078454	04-2004	Abrahams et al.	709/221
*	С	US-2003/0204597	10-2003	Arakawa et al.	709/226
*	D	US-2003/0225884	12-2003	Hayden, Mark G.	709/226
*	E	US-2003/0154281	08-2003	Mitsuoka et al.	709/225
*	F	US-2004/0143643	07-2004	Takamoto et al.	709/215
*	G	US-2005/0044198	02-2005	Okitsu et al.	709/223
*	Н	US-2007/0067428	03-2007	Ogawa et al.	709/223
*	ı	US-6,845,395	01-2005	Blumenau et al.	709/223
*	J	US-7,209,967	04-2007	Kitamura, Manabu	709/225
*	К	US-7,222,172	05-2007	Arakawa et al.	709/224
*	L	US-6,839,747	01-2005	Blumenau et al.	709/223
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					·
	Q					
	R					
	s					
	T					

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	·
	٧	
	w	
	·x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.